Special Issue

Sensing Technology in Artificial Intelligence and Intelligent Control Systems

Message from the Guest Editor

This Special Issue calls for high-quality, up-to-date research related to innovative sensor technologies for Sensing Technology in Artificial Intelligence and Intelligent Control.

- advanced sensor technology
- computer vision
- artificial intelligence
- image processing
- speech recognition
- pattern recognition
- knowledge extraction from sensing data
- intelligent control system
- applications of intelligent control system
- system parameter estimations
- neural network for control
- fuzzy and neuro-fuzzy systems for control
- evolutionary computation methods for control and parameter estimation
- machine learning for control systems /system parameter estimation
- reinforcement learning for control and parameter estimation

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Message from the Editor-in-Chief

Sensors is a leading journal devoted to fast publication of the latest achievements of technological developments and scientific research in the huge area of physical, chemical and biochemical sensors, including remote sensing and sensor networks. Both experimental and theoretical papers are published, including all aspects of sensor design, technology, proof of concept and application. Sensors organizes Special Issues devoted to specific sensing areas and applications each year.

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